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| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination OKAMURA, SEICHI | |
| | | Examiner Ryan Christensen | Art Unit 2856 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------|----------------|
| * | A | US-2003/0141456 | 07-2003 | Mc Neal et al. | 250/357.1 |
| * | B | US-6,853,199 | 02-2005 | Noik et al. | 324/637 |
| * | C | US-2,982,170 | 05-1961 | FELIX WYSS | 73/64.55 |
| * | D | US-3,499,154 | 03-1970 | BOYD DAVID M | 250/338.1 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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